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U.S. PATENT DOCUMENTS

Examiner Initial*		Document Number	Date	Name	Class	Sub Class	Filing Date If Appropriate

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub Class	Translation Yes or No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

M CB	IKOTA, M. et al., "Discrimination of Clustered Defects on Wafers Using Statistical Methods", Proc. 1997 Second Int. Workshop Statistical Metrology, pp. 52-55.

Examiner *Mary Catherine Basan*	Date Considered 2/7/04

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